Cut Ranking and Pruning: Enabling a General and Efficient FPGA Mapping Solution

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The cut generation, ranking, and pruning techniques introduced in this paper reduced the complexity and runtime of cut-based LUT mapping thereby contributing to the scalability of technology mapping for LUTs.

Since the earliest commercial FPGAs, the lookup-table has been the workhorse for implementing logic in most devices. The task of mapping logic to lookup-tables, called technology-mapping, is both central and unique to an FPGA CAD flow. It is not surprising then, that over the years, significant effort has been expended finding effective and efficient techniques to perform technology-mapping.

This paper, published in 1999, was neither the first nor the last paper on the subject. Previous algorithms such as FlowMap, Chortle, and DFmap had already been published, and it was well-known that efficient mapping of logic to lookup-tables was possible. Rather than just presenting a new algorithm, this paper presented techniques that were general enough to improve the efficiency of some of the core operations that are at the heart of almost any technology-mapping algorithm. In particular, this paper addressed cut generation, in which a collection of cuts are formed, cut ranking, in which the cuts are evaluated and ranked, and cut pruning, in which cuts that are not essential are discarded. For large circuits, these tasks are all computationally expensive, so efficient algorithms are essential to scale technology-mapping to large circuits. The authors also showed how these techniques can be applied to improve previously published algorithms.

Taken together, these techniques have since become an essential tool in any FPGA CAD algorithm designer’s arsenal and have been built upon numerous times. Today, technology-mapping is still an active research area (driven in part by fracturable LUTs and related innovations), and it is likely that the techniques from this 1999 paper will continue to influence the design and implementation of new technology-mapping algorithms.

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